

JRW



XA-9524C  
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

in re the application of:

Takahiro KASUGA et al.

Appln. No.: 10/626,670

Group Art Unit: 2811

Filed: July 25, 2003

Examiner: L. Tran

For: A SEMICONDUCTOR DEVICE AND A METHOD OF MANUFACTURING  
THE SAME

Allowed: September 2, 2004

Confirmation No.: 1826

\* \* \*

SECOND SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The documents on the attached List were cited in an Office Action in a counterpart Japanese patent application. Copies of the Office Action and an English Translation are attached.

The Commissioner is hereby authorized to charge to Deposit Account No. 50-1165 any fees under 37 C.F.R. §§ 1.16 and 1.17 that may be required by this paper and to credit any overpayment to that Account. If any extension of time is required in connection with the filing of this paper and has not been requested separately, such extension is hereby requested.



STATEMENT UNDER 37 C.F.R. § 1.97(e)

The undersigned hereby states that each item of information contained in this Supplemental Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,


MWS:sjk

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November 10, 2004

FORM PTO-1449				Atty. Docket No. XA-95234C		Appln. No. 10/626,670	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				Applicant Takahiro KASUGA et al.			
				Filing Date July 25, 2003		Group 2811	
				U.S. PATENT DOCUMENTS			
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AJ	2000-124240	04/28/00	Japan			Abstract
	AK	2000-150761	05/30/00	Japan			Abstract
	AL	9-153581	06/10/97	Japan			Abstract
	AM	11-220087	08/10/99	Japan			Abstract
	AN						
	AO						
OTHER (including author, title, date, pertinent pages, etc.)							
	AP						
	AQ						
	AR						
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							